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PRACTICE AREAS

Intellectual Property

INDUSTRIES

Disruptive Technology

Technology

COURT MEMBERSHIPS

- U.S. Patent and Trademark Office

EDUCATION

Harvard University, Ph.D in
Physics, 2006

Harvard University, M.S. in
Physics, 2002

Yale University, B.S. in Physics,
magna cum laude, 2000

Daniel M. Farkas, Ph.D.

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Dr. Daniel Farkas is an experimental physicist with over 18 years of laboratory experience in atomic, molecular, and optical physics. Specializing in managing technical research and development projects, he has worked with a host of technologies, including lasers and optics, photonics, vacuum systems, magnetics, electronics, and software.

Prior to joining the firm, Dr. Farkas served as both Manager of Contract Research and Development and Lead Scientist at a quantum technology development and design company. Here, he wrote over a dozen winning SBIR/STTR proposals, was principal investigator on nine government-sponsored research and development projects, and helped perform all aspects of project management.

Publications

- D. M. Farkas, E. A. Salim, and J. Ramirez-Serrano, "Production of Rubidium Bose-Einstein Condensates at a 1 Hz Rate," arXiv:1403.4641 (2014).
- D. M. Farkas, K. M. Hudek, S. Du, and D. Z. Anderson, "Efficient direct evaporative cooling in an atom-chip magnetic trap," Phys. Rev. A 87, 053417 (2013).
- D. M. Farkas, A. Zozulya, and D. Z. Anderson, "A compact, microchip atomic clock based on all-optical interrogation of ultracold trapped Rb atoms," Appl. Phys. B 101, pp. 705 - 721 (2011).
- D. M. Farkas, K. M. Hudek, E. A. Salim, S. R. Segal, M. B. Squires, and D. Z. Anderson, "A compact, transportable, microchip-based system for high repetition rate production of Bose-Einstein condensates," Appl. Phys. Lett. 96, 093102 (2010).
- T. Zelevinsky, D. Farkas, and G. Gabrielse, "Precision Measurement of the Three 23 PJ Fine Structure Intervals," Phys. Rev. Lett. 95,

203001 (2005).